

Search Notes

Application/Control No.

10/771,760

Examiner

Chau N. Nguyen

Applicant(s)/Patent under
Reexamination

DAUGHERTY ET AL.

Art Unit

2831

SEARCHED

Class	Subclass	Date	Examiner
174	75C	2/23/05	CN
	78	↓	↓
	74R	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR